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PATENT  
0465-0879P

IN THE U.S. PATENT AND TRADEMARK OFFICE

Applicants: Ha Zoong KIM                      Conf.: Unassigned  
Appl. No.: NEW                                      Group: Unassigned  
Filed: November 29, 2001                      Examiner: Unassigned  
For: DDB TEST PATTERN AND METHOD FOR TESTING TDDB OF  
MOS CAPACITOR DIELECTRIC

**PRELIMINARY AMENDMENT**

Assistant Commissioner for Patents  
Washington, D.C. 20231

November 29, 2001

Sir:

Prior to initial examination of this divisional application, please amend the  
above-identified application as follows:

**IN THE CLAIMS**

**Please cancel claims 1-10 without prejudice or disclaimer of the  
subject matter contained therein.**

**Please add the following additional claims:**

--13. (New) A unit test cell of a Time Dependent Dielectric Breakdown  
(TDDB) test pattern circuit, comprising:

a MOS capacitor with a first electrode connected to ground;

a MOS transistor with a source electrode connected to the first electrode of

00955680-112001  
FOOT-03956660

B<sup>1</sup>